

# Appendix



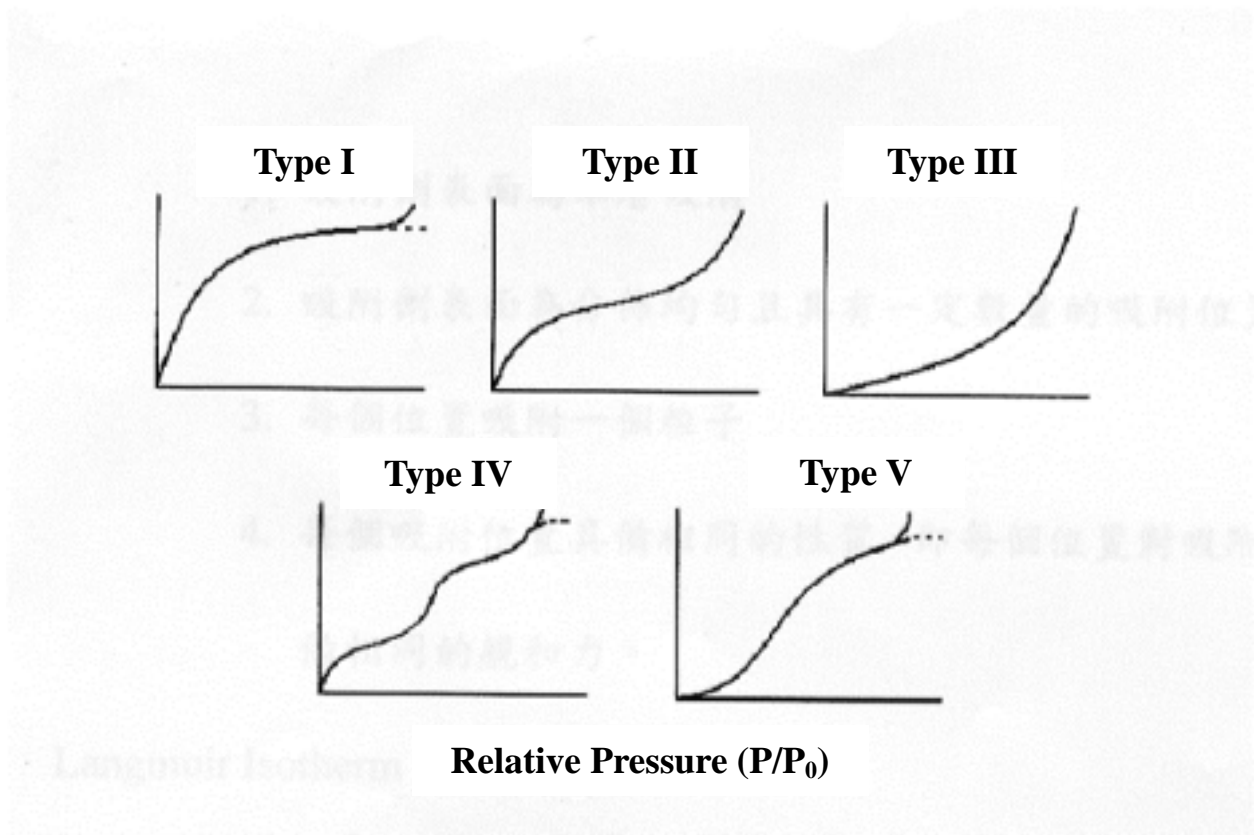


Fig. A-1. Types of Adsorption isotherms (蘇氏, 2004).

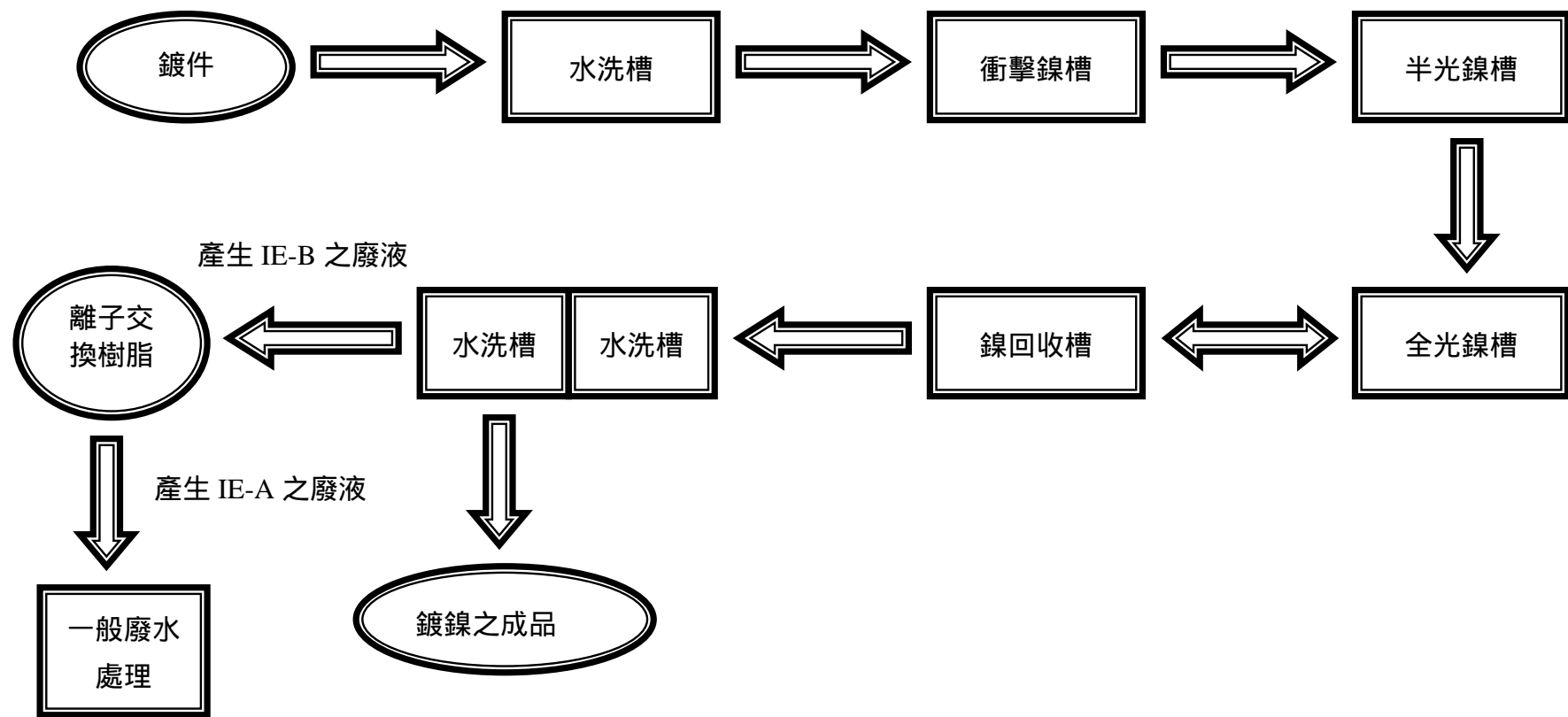


Fig. A-2. 電鍍製程及其廢水之產生流程

## Preset Sample Data

Sample Name:	<b>contained-sulfur drug</b>	Dilution Material:	
Description:		Sample Mass (g):	4.0000
Method:	Tq10701	Dilution Mass (g):	0.0000
Job Number:	950208	Dilution Factor:	1.0000
Sample State:	Cuvette, 28 mm	Sample rotation:	No
Sample Type:	Cuvette (liquid)	Date of Receipt:	2006/02/08
Sample Status:	AAAXXX	Date of Evaluation:	2008/02/08

## Results

The error is the statistical error with 1 sigma confidence interval

Full analysis			Sum	
			6.845	%
13	Al	<	1200	ppm/g
14	Si	<	150	ppm/g
15	P	<	56	ppm/g
16	S	34920 ±	60	ppm/g
17	Cl	33530 ±	50	ppm/g
19	K	<	38	ppm/g
20	Ca	<	10	ppm/g
21	Sc	6.8 ±	3.1	ppm/g
22	Ti	<	4.8	ppm/g
23	V	<	3.3	ppm/g
24	Cr	<	9.9	ppm/g
25	Mn	<	5.6	ppm/g
26	Fe	<	3.8	ppm/g
27	Co	<	2.5	ppm/g
28	Ni	<	1.7	ppm/g
29	Cu	<	1.3	ppm/g
30	Zn	<	1.0	ppm/g
31	Ga	<	0.8	ppm/g
33	As	<	0.7	ppm/g
35	Br	1.1 ±	0.1	ppm/g
38	Sr	0.4 ±	0.1	ppm/g
42	Mo	<	4.6	ppm/g
47	Ag	4.0 ±	1.2	ppm/g
48	Cd	<	5.0	ppm/g
49	In	5.6 ±	1.5	ppm/g
50	Sn	96.2 ±	2.1	ppm/g
51	Sb	9.7 ±	2.6	ppm/g
52	Te	<	89	ppm/g
53	I	<	29	ppm/g
56	Ba	111 ±	14	ppm/g
57	La	> 165 ±	16	ppm/g
58	Ce	> 307 ±	28	ppm/g
80	Hg	<	1.3	ppm/g
81	Tl	<	1.3	ppm/g
82	Pb	<	1.1	ppm/g
83	Bi	<	1.2	ppm/g

## Main components

16	S	3.492	±	0.006	%
17	Cl	3.353	±	0.005	%

Date: 2006/02/09

Page 1

Fig. A-3. Elements of contained-sulfur drug detected by XRF.

## Preset Sample Data

Sample Name:	<b>uncontained-sulfur drug</b>	Dilution Material:	
Description:		Sample Mass (g):	4.0000
Method:	Tq110701	Dilution Mass (g):	0.0000
Job Number:	950208	Dilution Factor:	1.0000
Sample State:	Cuvette, 28 mm	Sample rotation:	No
Sample Type:	Cuvette (liquid)	Date of Receipt:	2008/02/08
Sample Status:	A A A X X X	Date of Evaluation:	2006/02/08

## Results

The error is the statistical error with 1 sigma confidence interval

## Full analysis

13	Al	<	250	ppb/g	
14	Si	<	27	ppb/g	
15	P	<	6.7	ppb/g	
16	S	<	5.6	ppb/g	
17	Cl	965.0	±	4.3	ppb/g
19	K	<	22	ppb/g	
20	Ca	<	5.7	ppb/g	
21	Sc	6.4	±	1.8	ppb/g
22	Ti	<	2.0	ppb/g	
23	V	<	1.0	ppb/g	
24	Cr	<	7.0	ppb/g	
25	Mn	<	4.1	ppb/g	
26	Fe	<	2.7	ppb/g	
27	Co	<	1.7	ppb/g	
28	Ni	<	1.2	ppb/g	
29	Cu	<	0.9	ppb/g	
30	Zn	<	0.6	ppb/g	
31	Ga	<	0.6	ppb/g	
33	As	<	0.5	ppb/g	
35	Br	<	0.3	ppb/g	
38	Sr	<	0.3	ppb/g	
42	Mo	<	3.1	ppb/g	
47	Ag	4.7	±	1.0	ppb/g
48	Cd	3.5	±	1.0	ppb/g
49	In	6.2	±	1.3	ppb/g
50	Sn	79.0	±	1.8	ppb/g
51	Sb	6.9	±	2.3	ppb/g
52	Te	82	±	22	ppb/g
53	I	<	24	ppb/g	
56	Ba	<	47	ppb/g	
57	La	111	±	14	ppb/g
58	Ce	> 158	±	20	ppb/g
80	Hg	<	0.9	ppb/g	
81	Tl	<	0.9	ppb/g	
82	Pb	<	0.7	ppb/g	
83	Bi	<	0.8	ppb/g	

## Main components

Sum n. d.

Date: 2006/02/09

Page 1

Fig. A-4. Elements of contained-sulfur drug detected by XRF.

## Preset Sample Data

Sample Name:	<b>raw RH</b>	Dilution Material:	HWC
Description:		Sample Mass (g):	4.0000
Method:	Tq10701	Dilution Mass (g):	0.9000
Job Number:	940525	Dilution Factor:	0.8163
Sample State:	Pressed tablet, 32 mm	Sample rotation:	No
Sample Type:	Pressed tablet	Date of Receipt:	2005/05/25
Sample Status:	A A A X X X	Date of Evaluation:	2005/05/25

## Results

The error is the statistical error with 1 sigma confidence interval

## Full Analysis

12 Mg	<	0.50	%
13 Al	<	0.10	%
14 Si	11.14	± 0.01	%
15 P	0.09239	± 0.00049	%
16 S	1199	± 4	µg/g
17 Cl	1580	± 3	µg/g
19 K	1.096	± 0.004	%
20 Ca	0.2248	± 0.0018	%
22 Ti	<	0.0020	%
23 V	<	15	µg/g
24 Cr	55.4	± 3.7	µg/g
25 Mn	0.02352	± 0.00040	%
26 Fe	0.05248	± 0.00041	%
27 Co	<	2.6	µg/g
28 Ni	15.8	± 0.8	µg/g
29 Cu	7.9	± 0.6	µg/g
30 Zn	43.7	± 0.6	µg/g
31 Ga	<	0.7	µg/g
32 Ge	<	0.7	µg/g
33 As	<	0.6	µg/g
34 Se	<	0.3	µg/g
35 Br	1.8	± 0.1	µg/g
37 Rb	5.0	± 0.1	µg/g
38 Sr	0.00054	± 0.00001	%
39 Y	2.7	± 0.2	µg/g
40 Zr	<	50	µg/g
47 Ag	<	30	µg/g
48 Cd	<	30	µg/g
50 Sn	68.3	± 1.4	µg/g
51 Sb	<	6.0	µg/g
52 Te	<	59	µg/g
53 I	14.5	± 4.4	µg/g
56 Ba	146	± 11	µg/g
80 Hg	<	1.3	µg/g
81 Tl	<	1.1	µg/g
82 Pb	4.6	± 0.4	µg/g
83 Bi	<	1.2	µg/g
90 Th	<	1.2	µg/g
92 U	<	1.6	µg/g

## Main Compounds

14 Si	11.14	± 0.01	%
16 S	0.1198	± 0.0004	%
17 Cl	0.1580	± 0.0003	%
19 K	1.096	± 0.004	%
20 Ca	0.2248	± 0.0018	%
Sum		12.74	%

Fig. A-5. Elements of raw RH detected by XRF.

## Preset Sample Data

Sample Name:	<b>raw RHA</b>	Dilution Material:	
Description:		Sample Mass (g):	4.0000
Method:	Tqk10701	Dilution Mass (g):	0.0000
Job Number:	940525	Dilution Factor:	1.0000
Sample State:	Cuvette, 28 mm	Sample rotation:	No
Sample Type:	Cuvette (powder)	Date of Receipt:	2005/05/25
Sample Status:	A A A X X X	Date of Evaluation:	2005/05/25

## Results

The error is the statistical error with 1 sigma confidence interval

## Full Analysis

13	Al	<	0.10	%
14	Si	> 93.85	± 0.22	%
15	P	1.092	± 0.012	%
16	S	1704	± 22	mg/g
17	Cl	4052	± 24	mg/g
19	K	5.715	± 0.022	%
20	Ca	1.387	± 0.009	%
22	Ti	0.00494	± 0.00022	%
23	V	<	1.7	mg/g
24	Cr	220	± 10	mg/g
25	Mn	0.1453	± 0.0016	%
26	Fe	0.1274	± 0.0013	%
27	Co	<	7.9	mg/g
28	Ni	42.0	± 2.2	mg/g
29	Cu	13.4	± 1.6	mg/g
30	Zn	172.8	± 2.2	mg/g
31	Ga	<	2.1	mg/g
32	Ge	<	2.1	mg/g
33	As	3.5	± 0.7	mg/g
34	Se	<	0.9	mg/g
35	Br	2.7	± 0.3	mg/g
37	Rb	23.9	± 0.4	mg/g
38	Sr	0.00246	± 0.00004	%
39	Y	12.3	± 0.4	mg/g
40	Zr	<	50	mg/g
47	Ag	3.3	± 0.7	mg/g
48	Cd	<	4.4	mg/g
50	Sn	35.6	± 1.0	mg/g
51	Sb	<	8.7	mg/g
52	Te	<	58	mg/g
53	I	<	12	mg/g
56	Ba	95.3	± 7.0	mg/g
80	Hg	<	3.9	mg/g
81	Tl	<	3.0	mg/g
82	Pb	18.5	± 1.0	mg/g
83	Bi	<	3.4	mg/g
90	Th	<	3.4	mg/g
92	U	<	5.1	mg/g

## Main Compounds

15	P	1.092	± 0.012	%
16	S	0.1704	± 0.0022	%
17	Cl	0.4052	± 0.0024	%
19	K	5.715	± 0.022	%
20	Ca	1.387	± 0.009	%
25	Mn	0.1453	± 0.0016	%
26	Fe	0.1274	± 0.0013	%
Sum		102.9		%

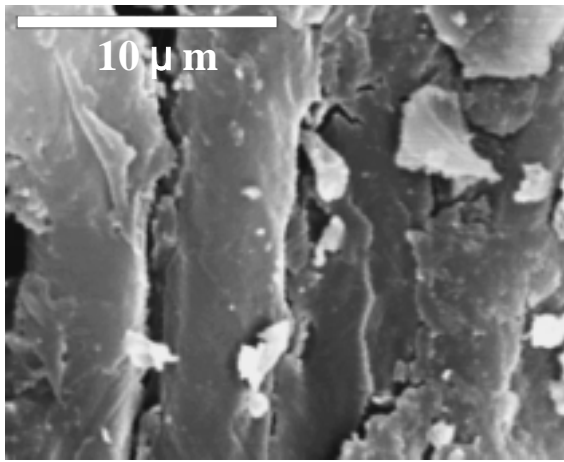
## Main Compounds

14	Si	> 93.85	± 0.22	%
----	----	---------	--------	---

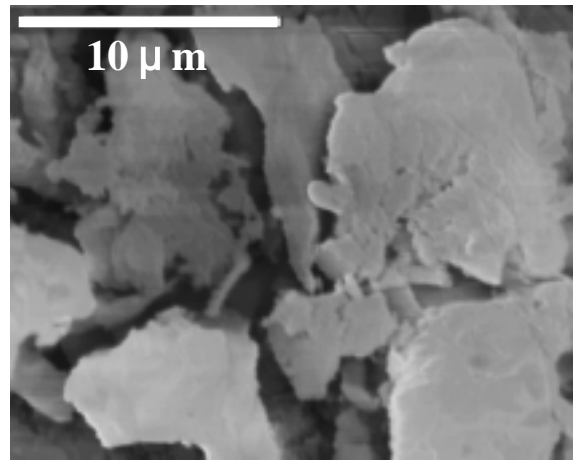
Date: 2005/05/26

Page 6

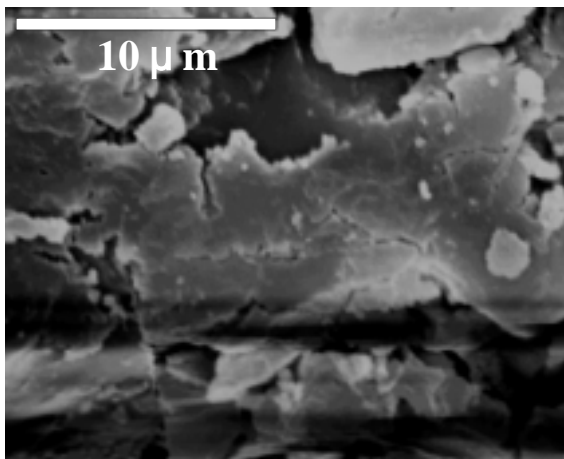
Fig. A-6. Elements of raw RHA detected by XRF.



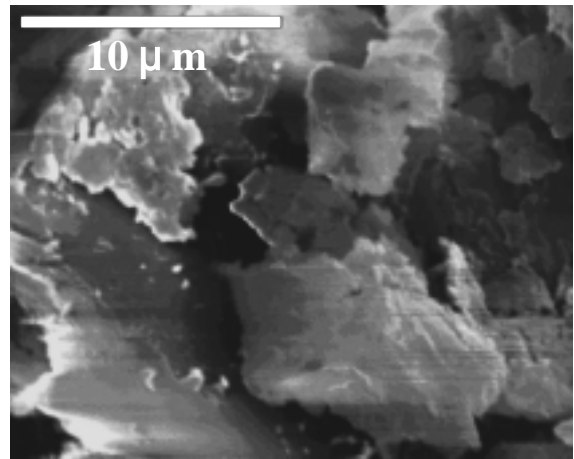
raw RH



RH-Ni (NiSO<sub>4</sub>)-0.5 h



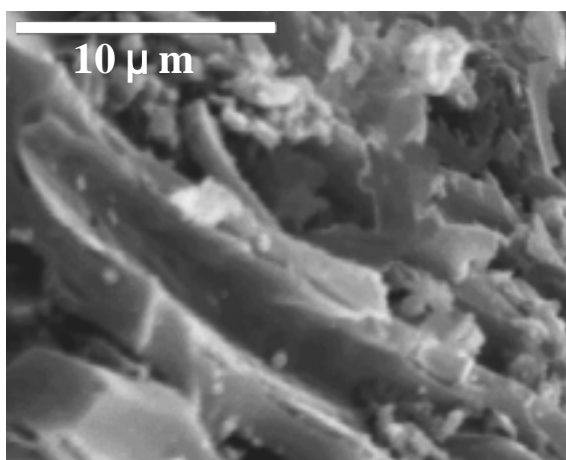
RH-Ni (NiSO<sub>4</sub>)-12 h



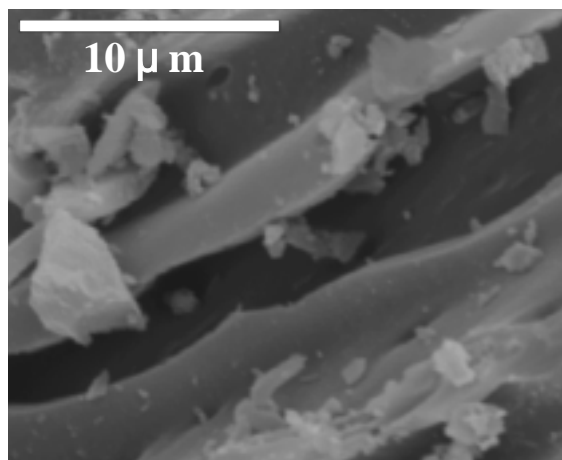
RH-Ni (NiSO<sub>4</sub>)-24 h

Fig. A-7. Morphology (x 5000) of raw RH and the RH samples that sorb nickel from 2000 mg/L Ni (II) solution for 0.5, 12 and 24 h.

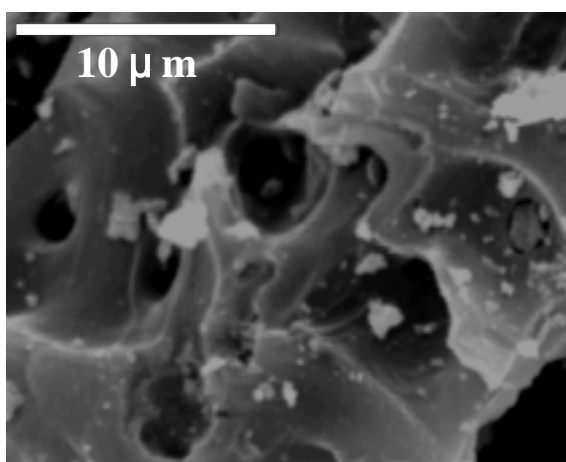




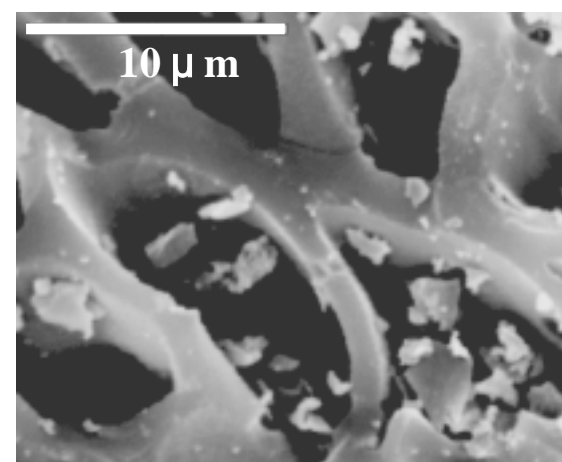
raw RHA



RHA-Ni (NiSO<sub>4</sub>)-0.5 h



RHA-Ni (NiSO<sub>4</sub>)-12 h



RHA-Ni (NiSO<sub>4</sub>)-24 h

Fig. A-8. Morphology (x 5000) of raw RHA and and the RHA samples that sorb nickel from 2000 mg/L Ni (II) solution for 0.5, 12 and 24h.

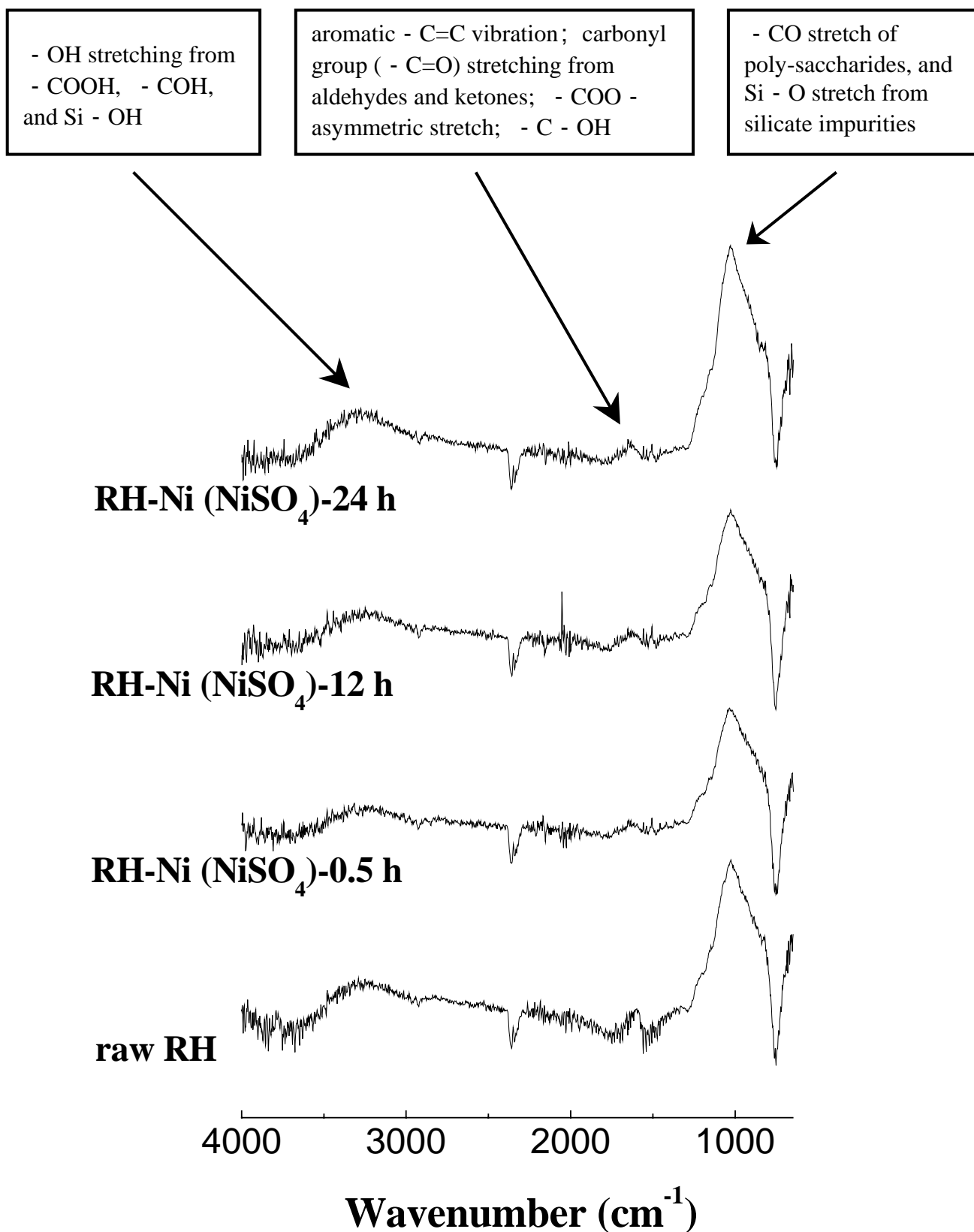


Fig. A-9. FT-IR spectra of raw RH and the RH samples that sorb nickel from 2000 mg/L Ni (II) solution for 0.5, 12 and 24h.

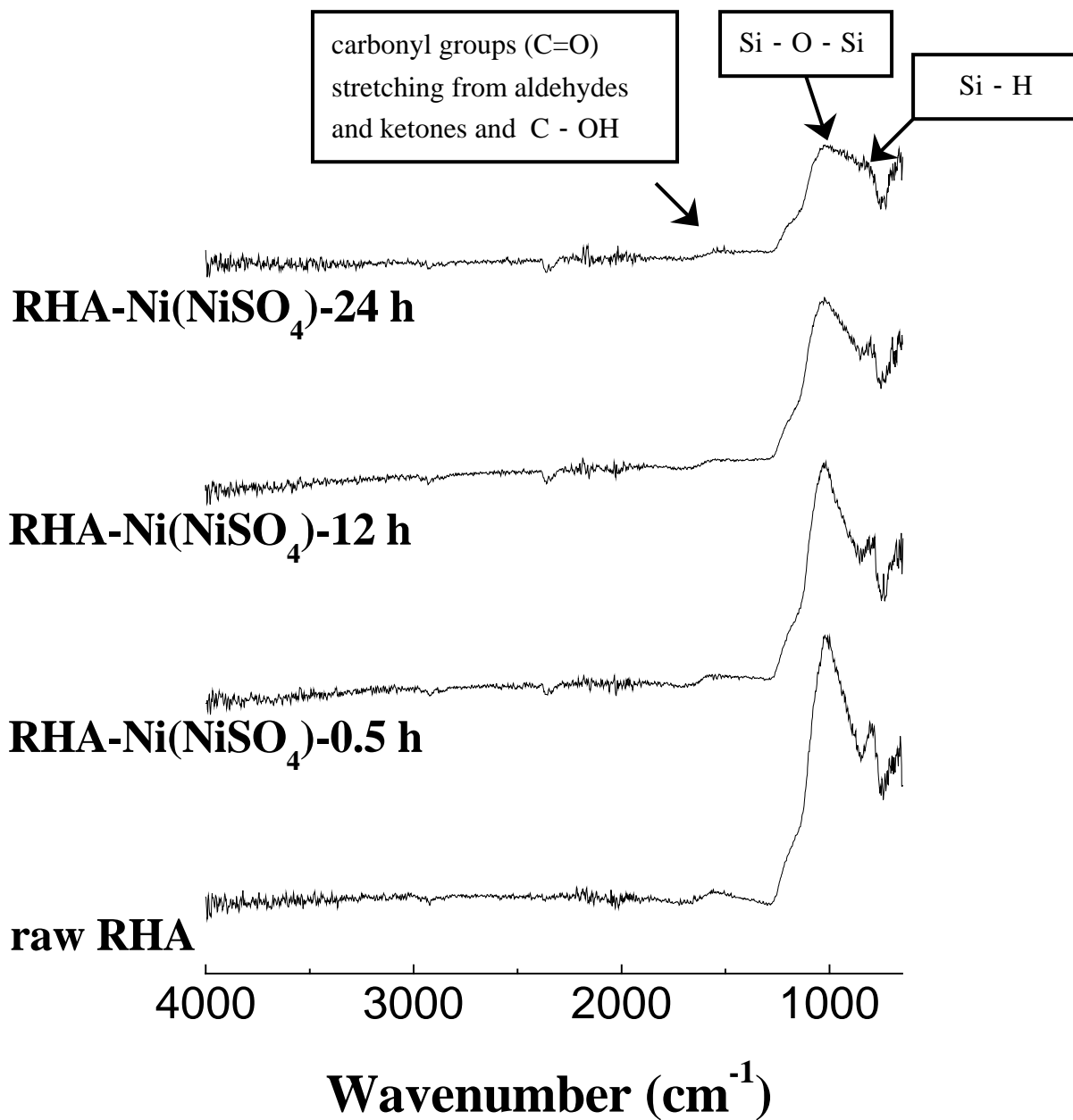
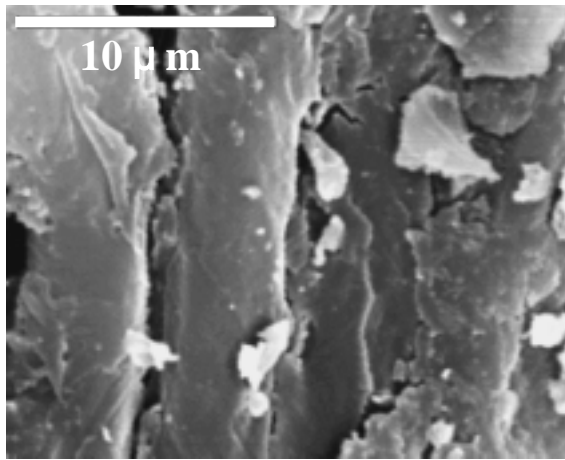
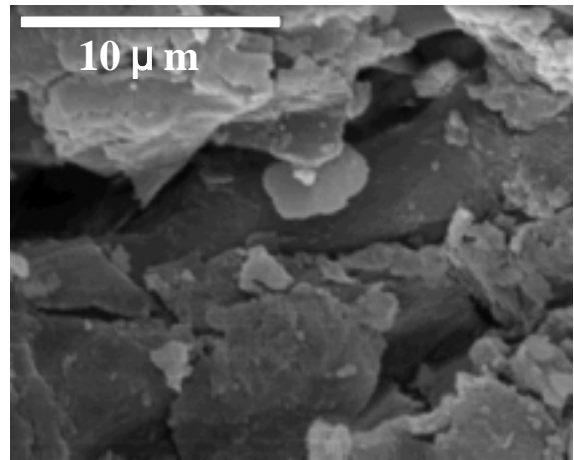


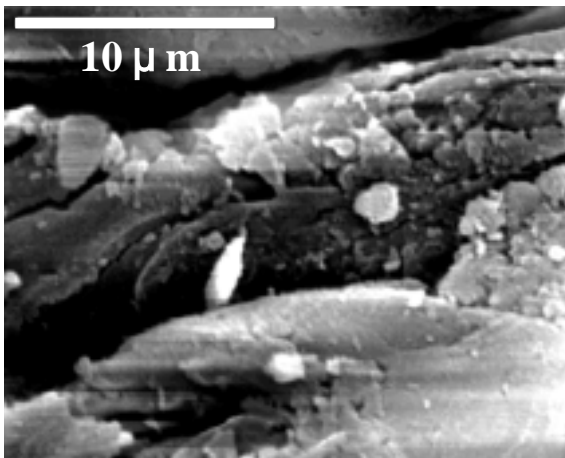
Fig. A-10. FT-IR spectra of raw RHA and the RHA samples that sorb nickel from 2000 mg/L Ni (II) solution for 0.5, 12 and 24h.



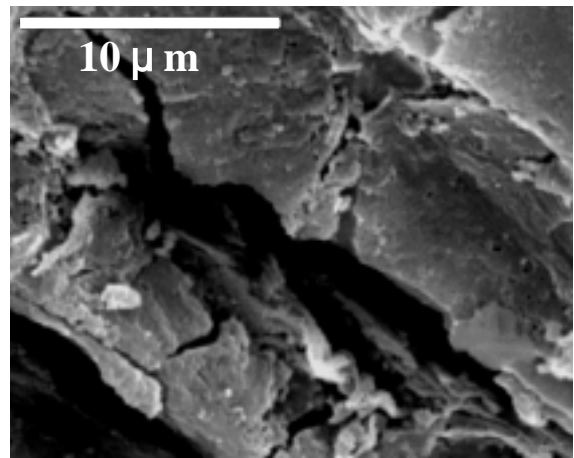
raw RH



RH-Ni (plating)-0.5 h

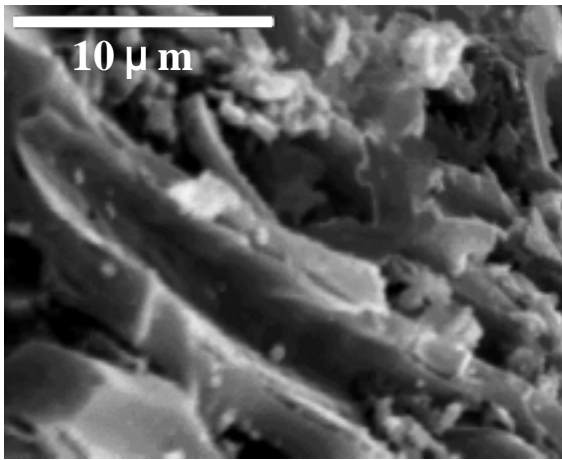


RH-Ni (plating)-12 h

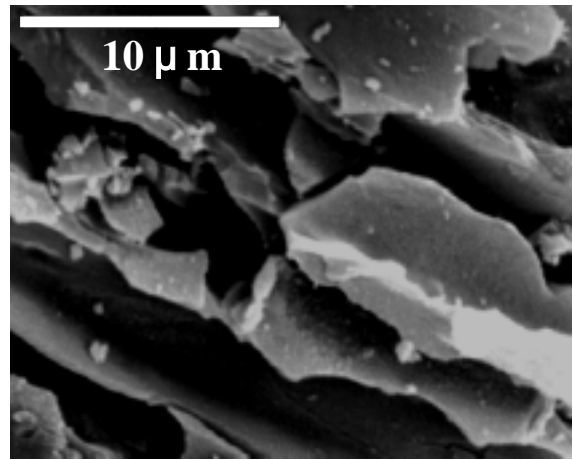


RH-Ni (plating)-24 h

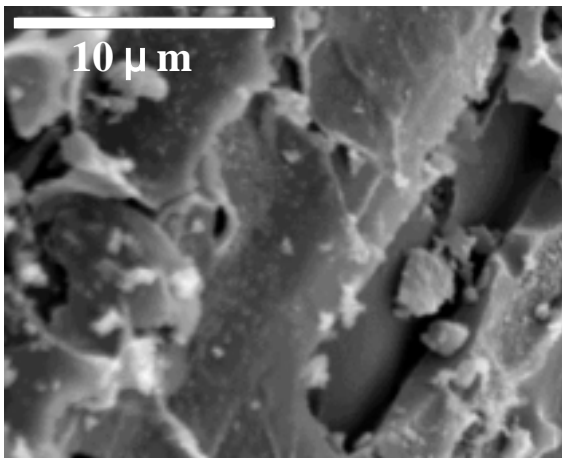
Fig. A-11. Morphology (x5000) of raw RH and the RH samples that sorb nickel from plating wastewater for 0.5, 12, 24 h.



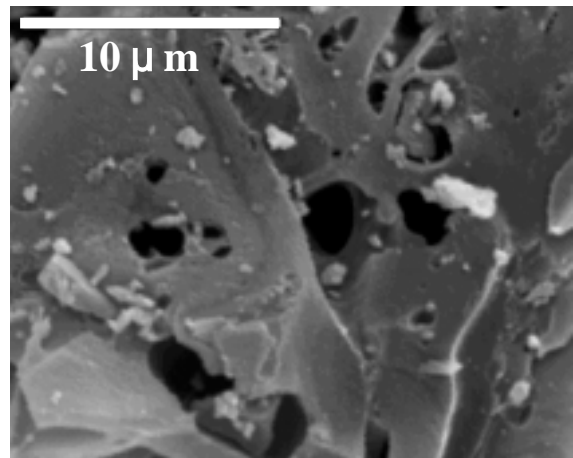
raw RHA



RHA-Ni (plating)-0.5 h



RHA- Ni (plating)-12 h



RHA- Ni (plating)-24 h

Fig. A-12. Morphology (x5000) of raw RHA and the RHA samples that sorb nickel from plating wastewater for 0.5, 12, 24 h.

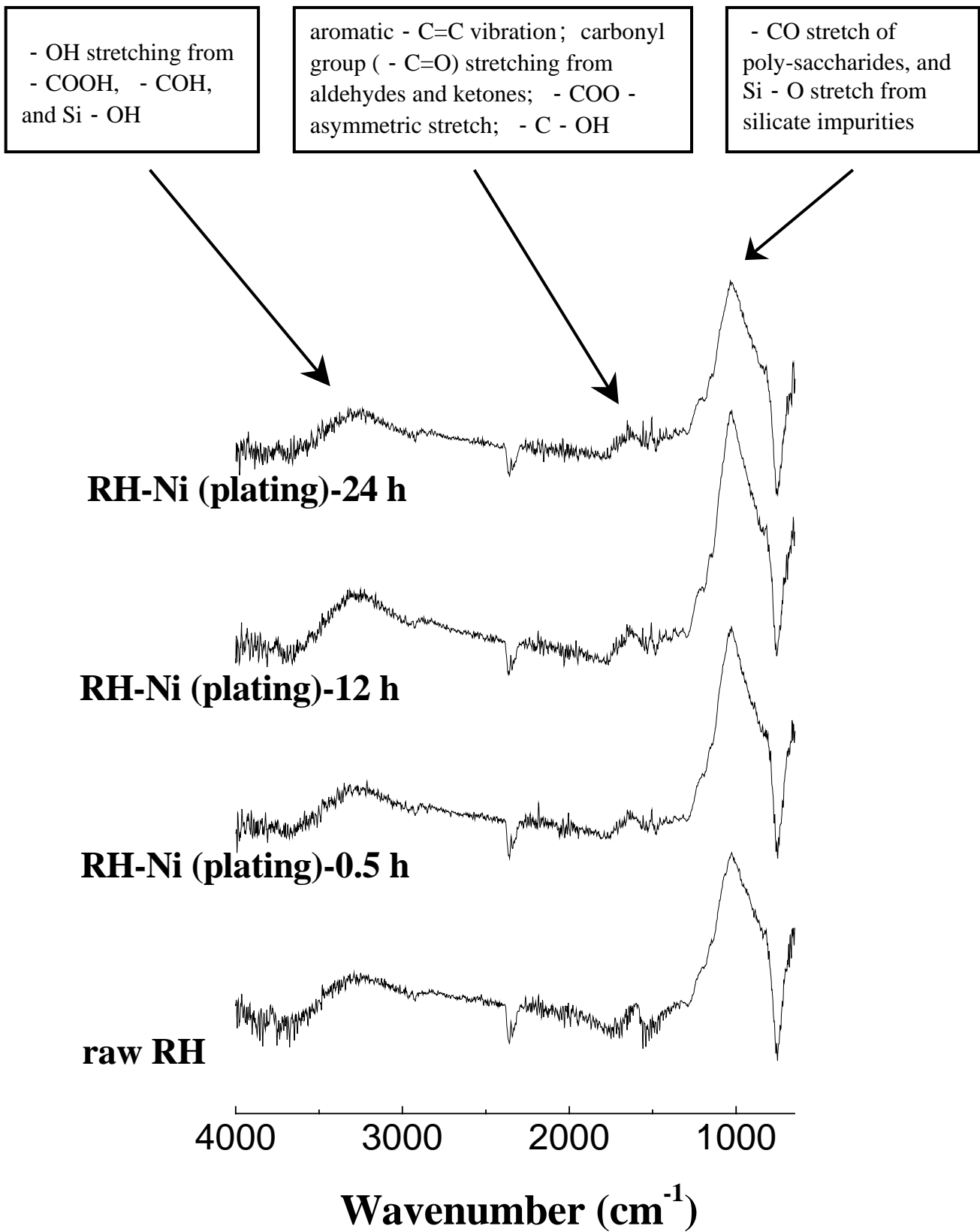


Fig. A-13. FT-IR spectra of raw RH and the RH samples that sorb nickel from plating wastewater for 0.5, 12 and 24h.

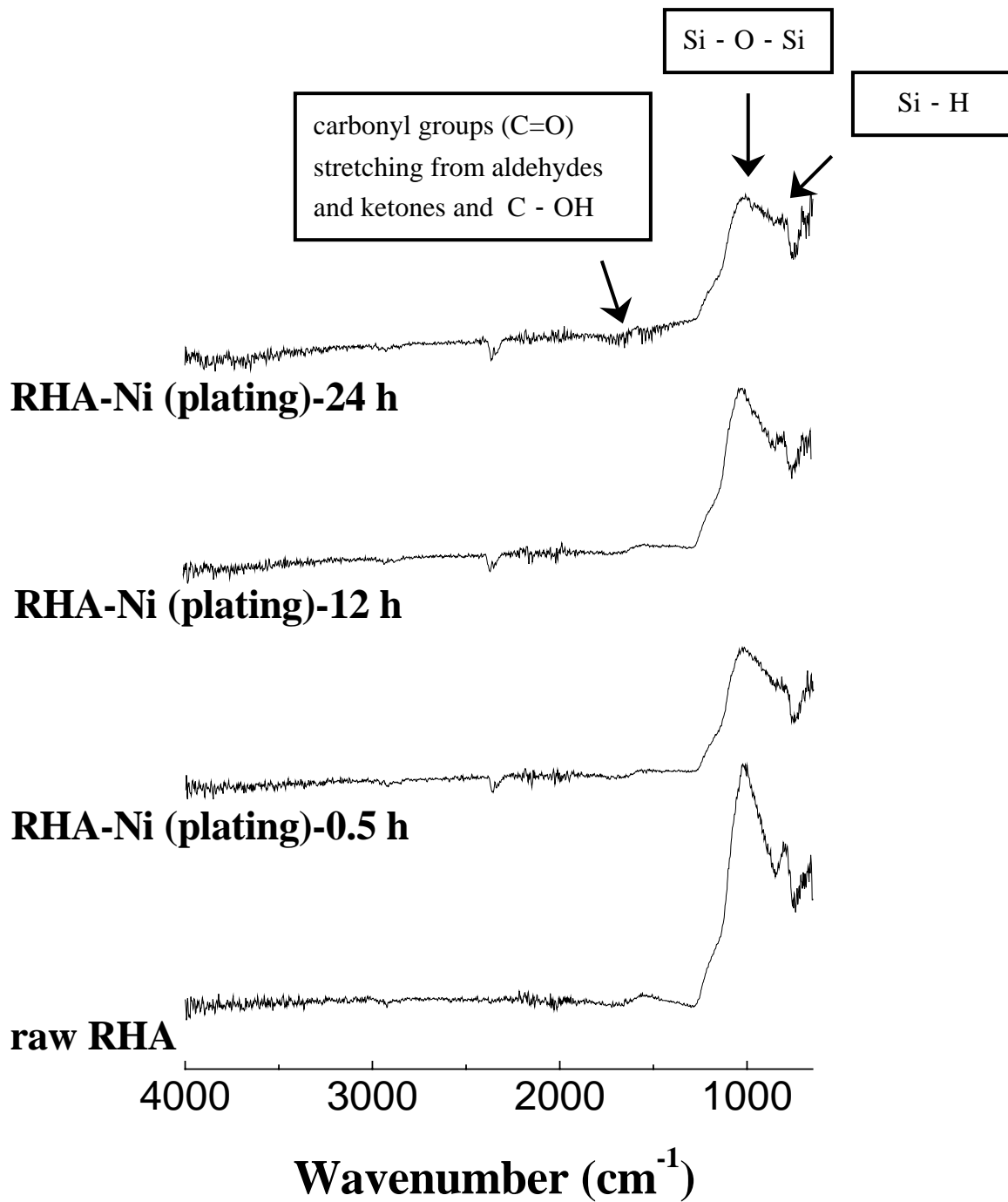
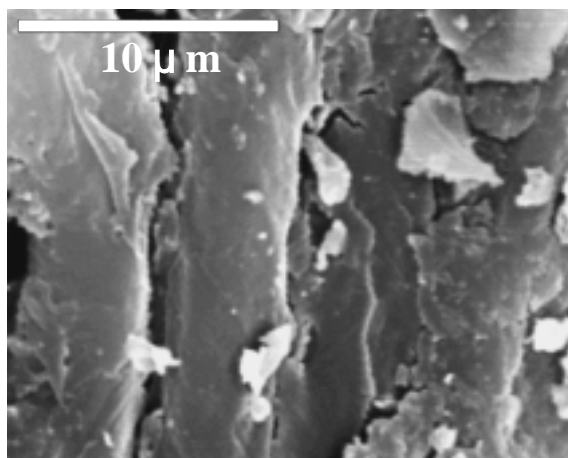
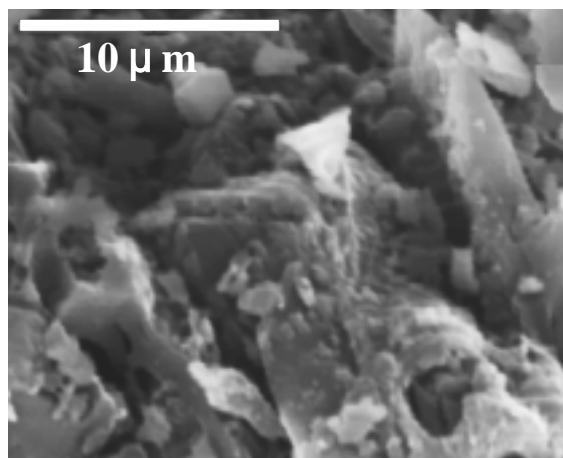


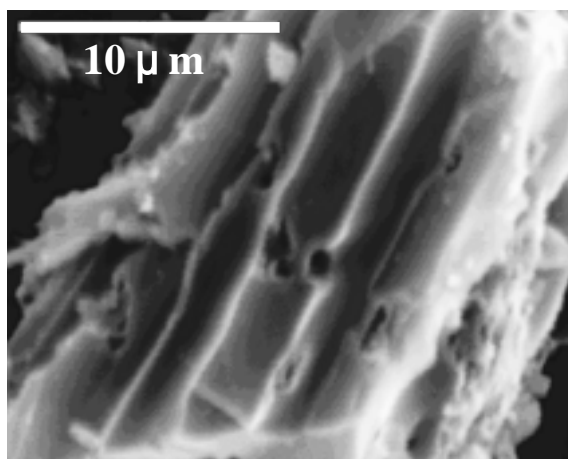
Fig. A-14. FT-IR spectra of raw RHA and the RHA samples that sorb nickel from plating wastewater for 0.5, 12 and 24h.



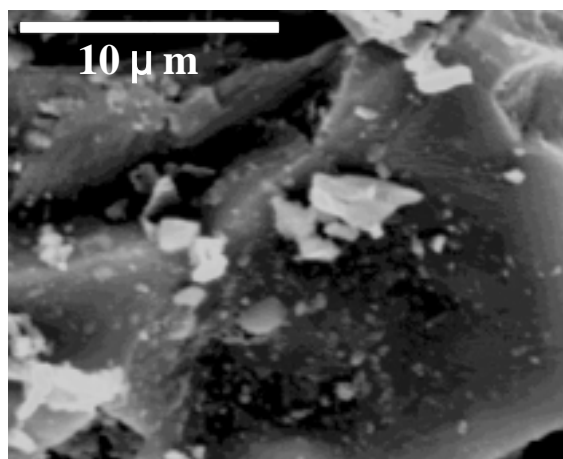
raw RH-105 °C



raw RH-500 °C



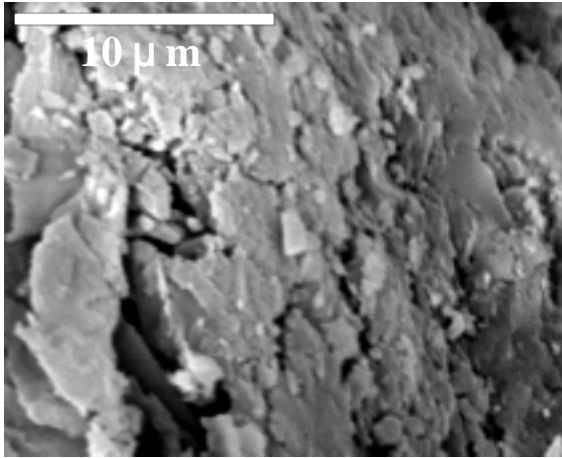
raw RH-900 °C



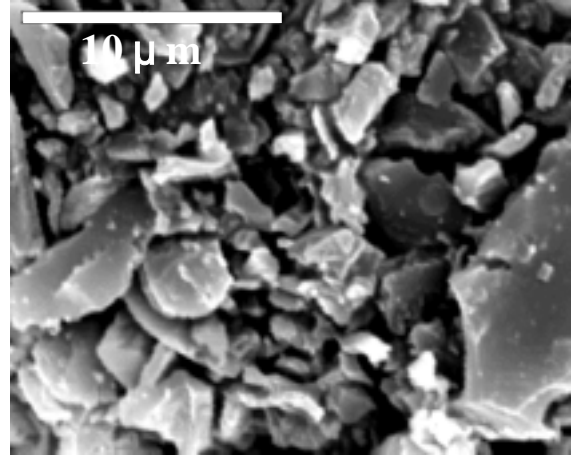
raw RH-1100 °C

Fig. A-15. Morphology (x5000) of raw RH samples after heating at different temperatures.

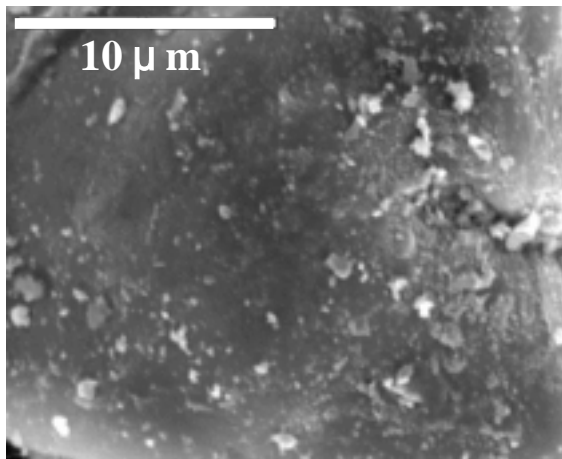




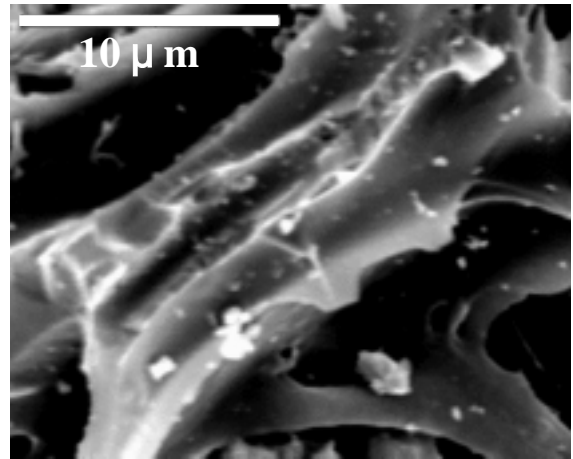
RH-Ni (NiSO<sub>4</sub>)-105 °C



RH-Ni (NiSO<sub>4</sub>)-500 °C



RH-Ni (NiSO<sub>4</sub>)-900 °C



RH-Ni (NiSO<sub>4</sub>)-1100 °C

Fig. A-16. Morphology (x5000) of Ni (NiSO<sub>4</sub>)-containing RH samples after heating at different temperatures.

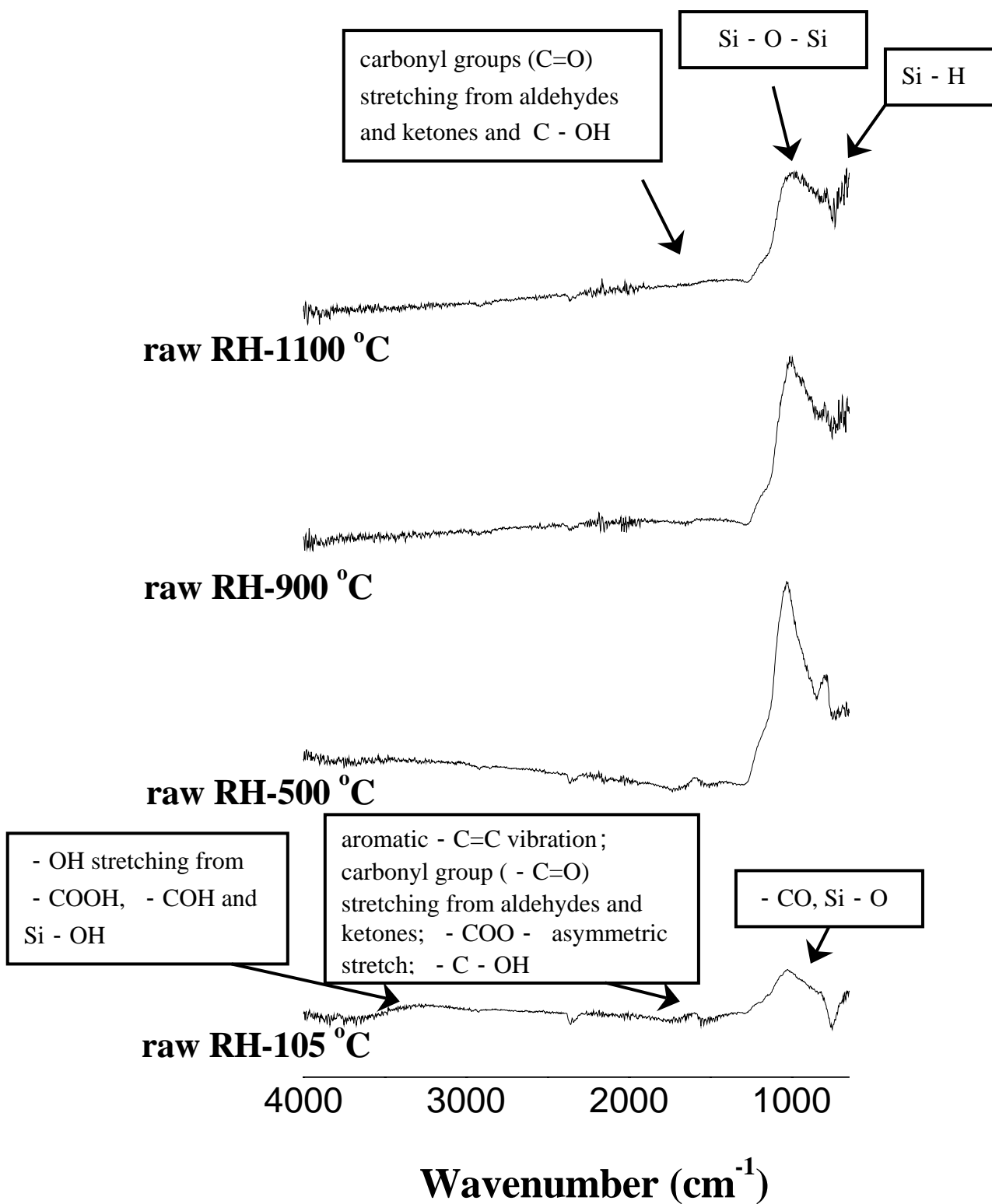


Fig. A-17. FT-IR spectra of raw RH samples after heating at different temperatures.

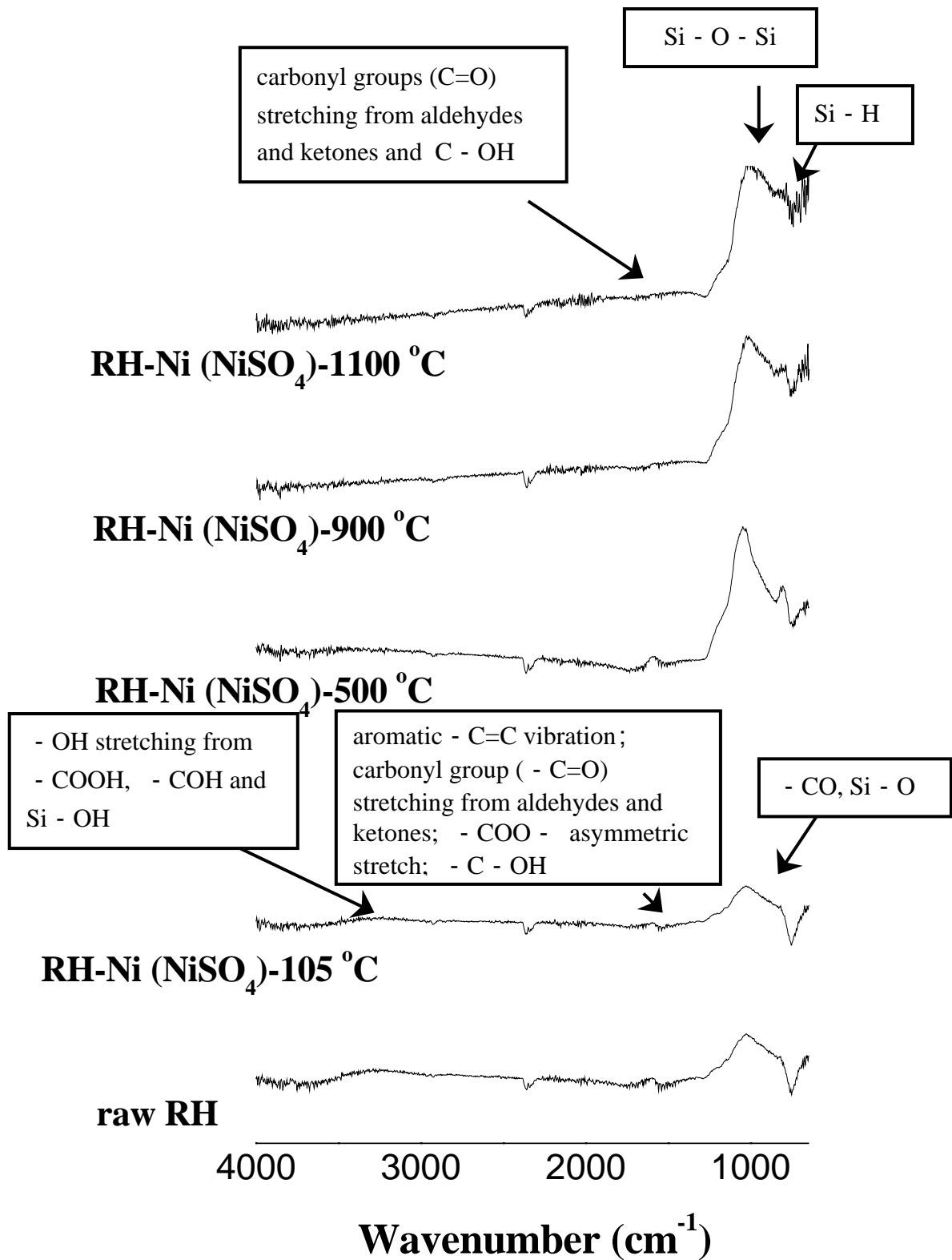
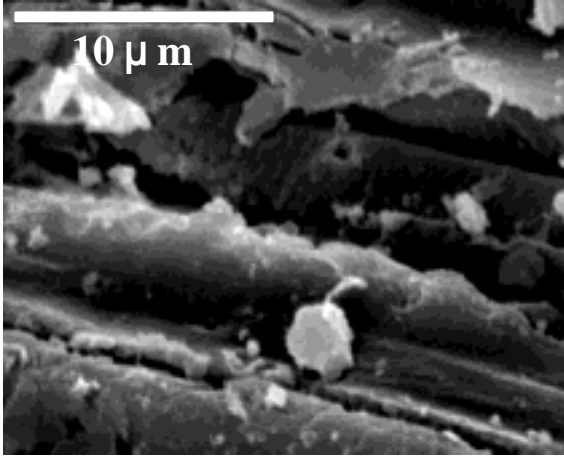
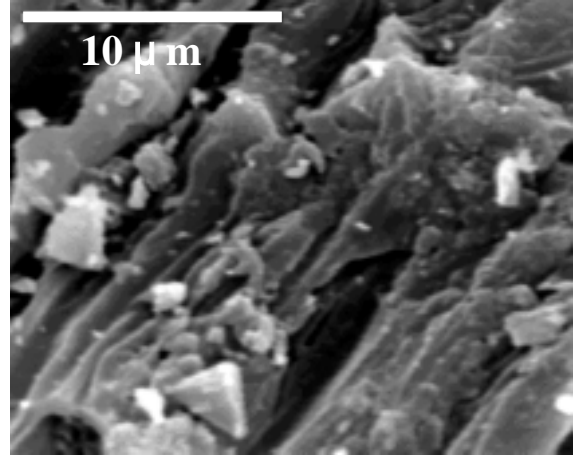


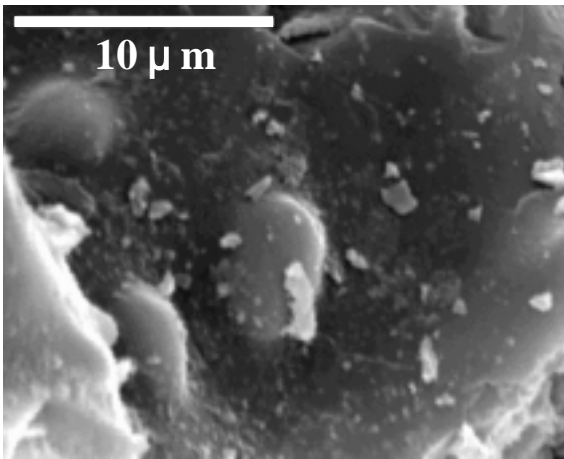
Fig. A-18. FT-IR spectra of raw RH and heated Ni (NiSO<sub>4</sub>)-containing RH samples at different temperatures.



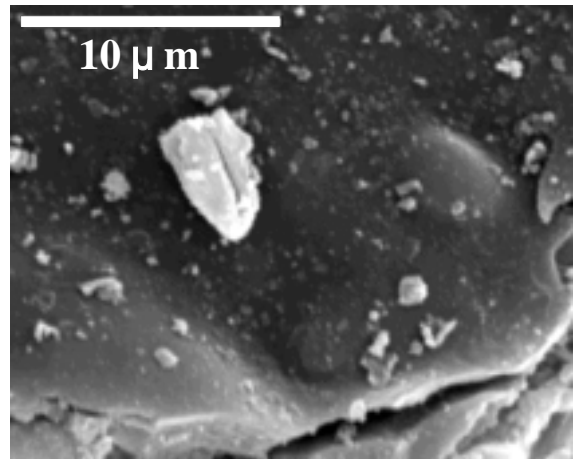
RH-Ni (plating)-105 °C



RH- Ni (plating)-500 °C



RH- Ni (plating)-900 °C



RH- Ni (plating)-1100 °C

Fig. A-19. Morphology (x5000) of Ni (plating)-containing RH samples after heating at different temperatures.

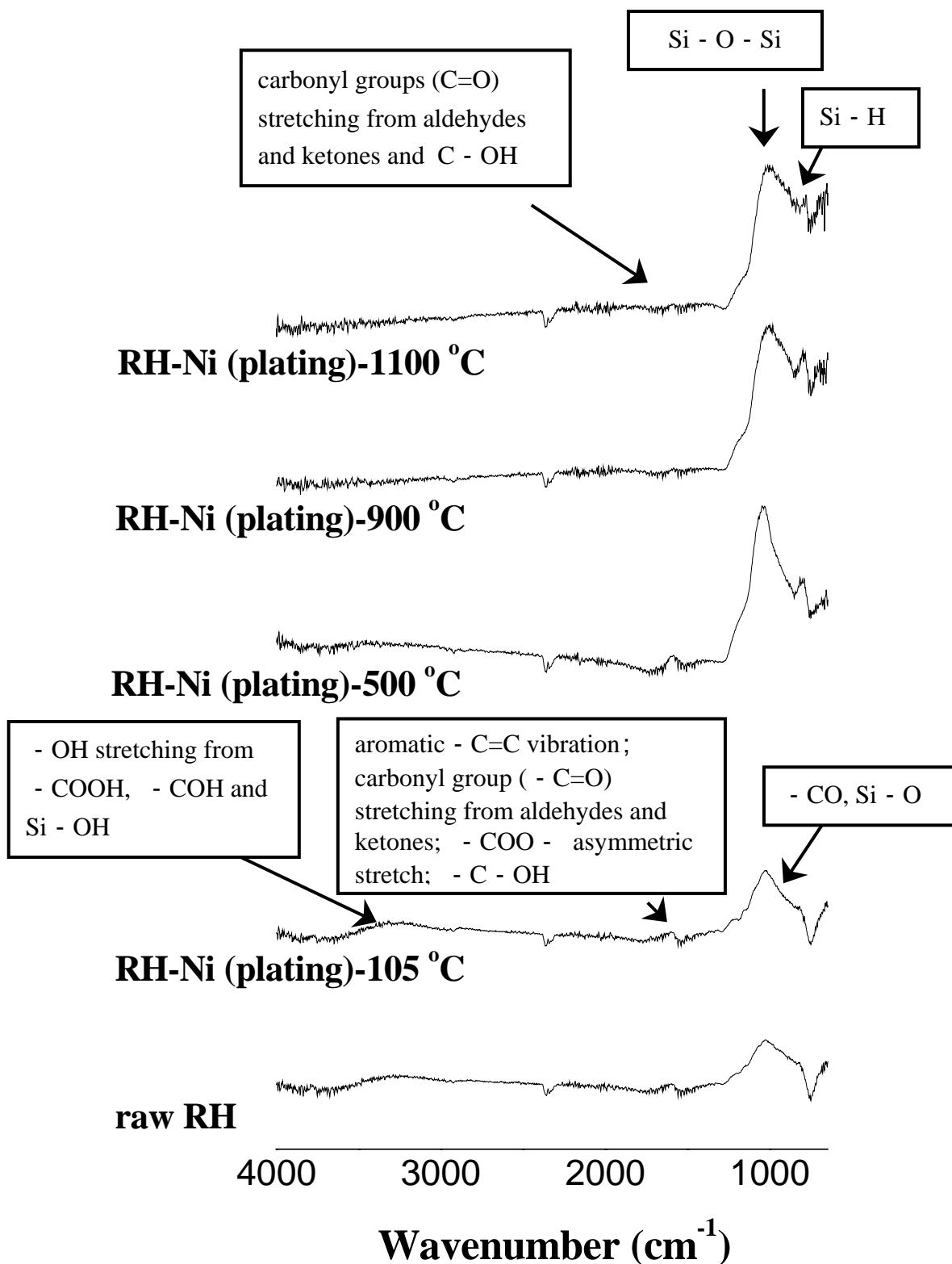


Fig. A-20. FT-IR spectra of raw RH and Ni (plating)-containing RH samples after heating at different temperatures.

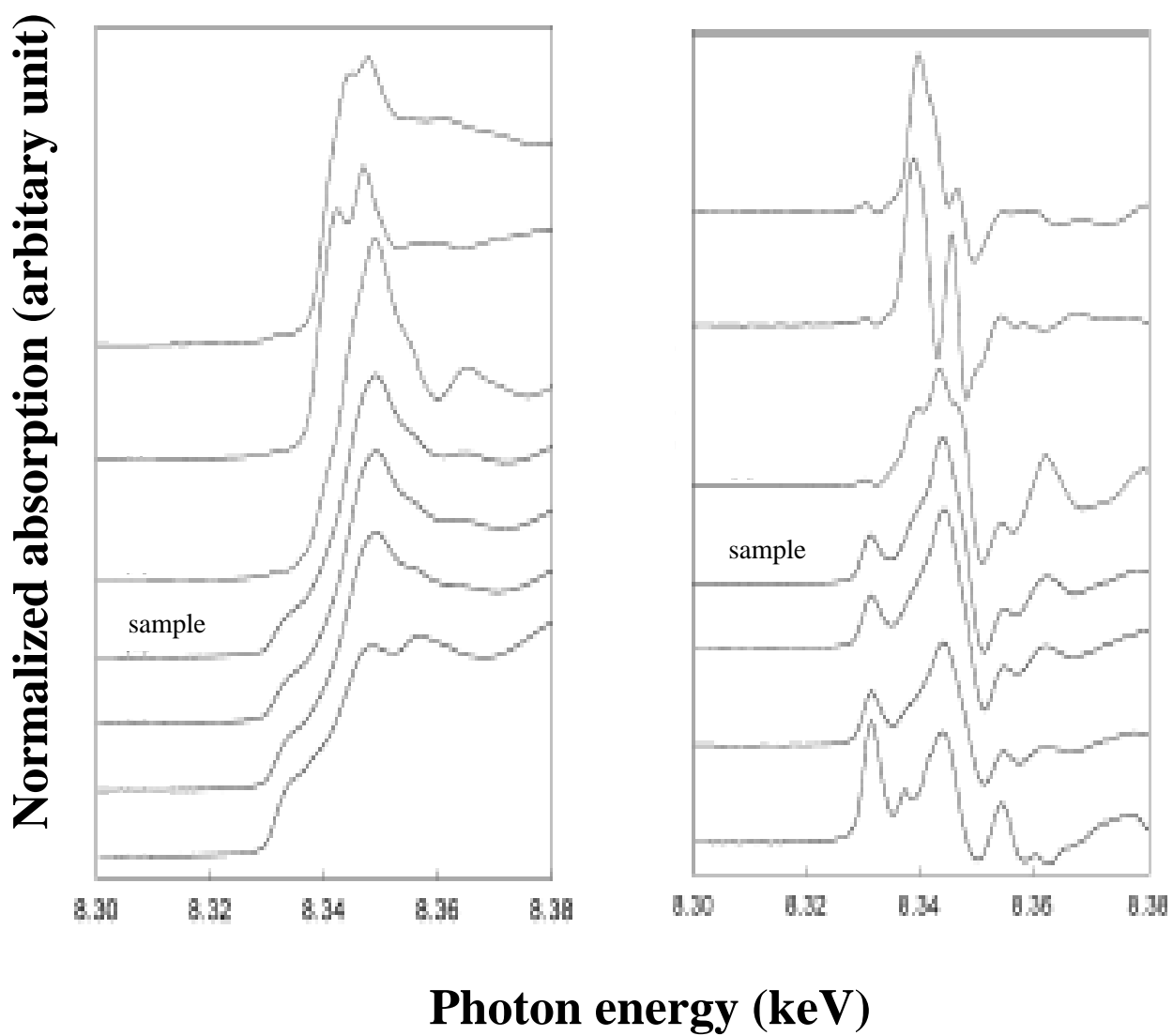


Fig. A-21.. XANES spectra and their first derivative spectra of raw Ni / SiO<sub>2</sub> sample

【Murthy, et al., 2004】 .